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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

B. S. Beaman et al.

Serial No.: 09/251,988

Filed: February 17, 1999

Date: April 11, 2003

Group Art Unit: 2829

Examiner: J. M. Hollington

Docket No.: YO999-088

For: STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE  
POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY

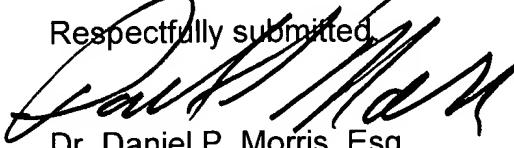
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**INFORMATION DISCLOSURE STATEMENT**  
**TRANSMITTAL LETTER**

Sir:

Please find enclosed a listing (PTO Form 1449) of references which may be relevant to the above-referenced application. This listing of references is not a representation that a search has been made, that better references than listed do not exist, or that other references are not applicable. Moreover, this listing does not constitute any admission by applicants or applicants' attorney that the information provided herein is necessarily prior art to applicants' invention. Please charge any fee necessary to enter this paper to deposit account 09-0468.

Respectfully submitted,



Dr. Daniel P. Morris, Esq.  
Reg. No. 32,053  
(914) 945-3217

IBM Corporation  
Intellectual Property Law Dept.  
P.O. Box 218  
Yorktown Heights, New York 10598



APR 1 1 2003

PTO-1449 (Modified)

**LIST OF PATENTS AND PUBLICATIONS  
FOR APPLICANT'S INFORMATION  
DISCLOSURE STATEMENT**
**ATTY. DOCKET NO.**

YO999-088

**SERIAL NO.: 09/251,988****APPLICANT:**

B. S. Beaman et al.

**FILING DATE:**

February 17, 1999

**GROUP: 2829****REFERENCE DESIGNATION****U.S. PATENT DOCUMENTS**

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
AA	5,367,254	11/22/1994	Faure et al.			
AB						
AC						
AD						
AE						
AF						

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
AG								
AH								
AI								
AJ								
AK								
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**OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)**

AN	
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EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.